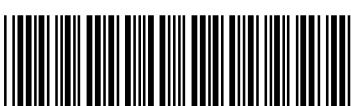


Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10560517	ALI-HACKL ET AL.
	Examiner	Art Unit
	HUY D NGUYEN	2617

SEARCHED

Class	Subclass	Date	Examiner
370	350, 318	10/23/2008	HN
455	13.4, 522, 127.1	10/23/2008	HN
Updated search	same as above	4/27/2009	HN

SEARCH NOTES

Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	10/23/2008	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	4/27/2009	HN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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